

Robust Parameter Design

- Statistical/engineering method for product/process improvement (Taguchi).
- Two types of factors in a system (product/process):
 - control factors: once chosen, values remain fixed.
 - noise factors: hard-to-control during normal process or usage.
- **Robust Parameter design (RPD or PD)**: choose control factor settings to make response less sensitive (i.e., more robust) to noise variation; exploiting control-by-noise interactions.

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A Robust Design Perspective of Layer-growth and Leaf Spring Experiments

- The original AT&T layer growth experiment had
 - 8 control factors,
 - 2 noise factors (location and facet).

Goal was to achieve *uniform* thickness around $14.5\ \mu\text{m}$ over the noise factors. See Tables 1 and 2 (LNp.10-3~4).
- The original leaf spring experiment had
 - 4 control factors,
 - 1 noise factor (quench oil temperature). The quench oil temperature is not controllable; with efforts it can be set in two ranges of values 130-150, 150-170.

Goal is to achieve *uniform* free height around 8 inches over the range of quench oil temperature. See Tables 3 and 4 (LNp.10-5).
- Must understand the role of *noise factors* in achieving *robustness*.





Layer Growth Experiment: Factors and Levels

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Table 1: Factors and Levels, Layer Growth Experiment

Control Factor		Level	
		—	+
A.	susceptor-rotation method	continuous	oscillating
B.	code of wafers	668G4	678D4
C.	deposition temperature(°C)	1210	1220
D.	deposition time	short	long
E.	arsenic flow rate(%)	55	59
F.	hydrochloric acid etch temperature(°C)	1180	1215
G.	hydrochloric acid flow rate(%)	10	14
H.	nozzle position	2	6
Noise Factor		Level	
		—	+
L.	location	bottom	top
M.	facet	1 2	3 4



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Layer Growth Experiment: Thickness Data

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Table 2: Cross Array and Thickness Data,
Layer Growth Experiment

Control Factor								Noise Factor			
								L-Bottom		L-Top	
A	B	C	D	E	F	G	H	M-1	M-2	M-3	M-4
—	—	—	+	—	—	—	—	14.2908	14.1924	14.2714	14.1876
—	—	—	+	+	+	+	+	14.8030	14.7193	14.6960	14.7635
—	—	+	—	—	—	+	+	13.8793	13.9213	13.8532	14.0849
—	—	+	—	+	+	—	—	13.4054	13.4788	13.5878	13.5167
—	+	—	—	—	+	—	+	14.1736	14.0306	14.1398	14.0796
—	+	—	—	+	—	+	—	13.2539	13.3338	13.1920	13.4430
—	+	+	+	—	+	+	—	14.0623	14.0888	14.1766	14.0528
—	+	+	+	+	—	—	+	14.3068	14.4055	14.6780	14.5811
+	—	—	—	—	+	+	—	13.7259	13.2934	12.6502	13.2666
+	—	—	—	+	—	—	+	13.8953	14.5597	14.4492	13.7064
+	—	+	+	—	+	—	+	14.2201	14.3974	15.2757	15.0363
+	—	+	+	+	—	+	—	13.5228	13.5828	14.2822	13.8449
+	+	—	—	—	—	+	+	14.5335	14.2492	14.6701	15.2799
+	+	—	+	+	+	—	—	14.5676	14.0310	13.7099	14.6375
+	+	+	—	—	—	—	—	12.9012	12.7071	13.1484	13.8940
+	+	+	—	+	+	+	+	13.9532	14.0830	14.1119	13.5963





Leaf Spring Experiment

Table 3: Factors and Levels,
Leaf Spring Experiment

Control Factor	Level	
	–	+
B. high heat temperature (°F)	1840	1880
C. heating time (seconds)	23	25
D. transfer time (seconds)	10	12
E. hold down time (seconds)	2	3
Noise Factor	Level	
	–	+
Q. quench oil temperature (°F)	130-150	150-170

Table 4: Cross Array and Height Data,
Leaf Spring Experiment

Control Factor	Noise Factor					
	B	C	D	E	Q [–]	Q ⁺
– + + –	7.78	7.78	7.81	7.50	7.25	7.12
+ + + +	8.15	8.18	7.88	7.88	7.88	7.44
– – + +	7.50	7.56	7.50	7.50	7.56	7.50
+ – + –	7.59	7.56	7.75	7.63	7.75	7.56
– + – +	7.94	8.00	7.88	7.32	7.44	7.44
+ + – –	7.69	8.09	8.06	7.56	7.69	7.62
– – – –	7.56	7.62	7.44	7.18	7.18	7.25
+ – – +	7.56	7.81	7.69	7.81	7.50	7.59

❖ Reading: textbook, 11.1

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Strategies for Variation Reduction

1. **Sampling inspection:** passive, sometimes last resort.
2. **Control charting and process monitoring:** can remove special causes. If the process is stable, it can be followed by using a *designed experiment*.
3. **Blocking, covariate adjustment:** passive measures but useful in reducing variability, not for removing root causes.
4. **Reducing variation in noise factors:** effective as it may reduce variation in the response but can be expensive. Better approach is to change control factor settings (*cheaper* and *easier* to do) by exploiting control-by-noise interactions, i.e., use robust parameter design!

❖ Reading: textbook, 11.2

Types of Noise Factors

1. Variation in process parameters.
2. Variation in product parameters.
3. Environmental variation.
4. Load Factors.
5. Upstream variation.
6. Downstream or user conditions.
7. Unit-to-unit and spatial variation.
8. Variation over time.
9. Degradation.

- **Traditional design uses 7 and 8.**

❖ **Reading:** textbook, 11.3

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Variation Reduction Through RPD

- Suppose $y = f(\mathbf{x}, \mathbf{z})$, \mathbf{x} control factors and \mathbf{z} noise factors. If \mathbf{x} and \mathbf{z} interact in their effects on y , then the $\text{var}_{\mathbf{z}}(y)$ can be reduced either by reducing $\text{var}(\mathbf{z})$ (i.e., method 4 in LNp.10-6) or by changing the \mathbf{x} values (i.e., RPD).
- An example:

$$\begin{aligned} y &= \mu + \alpha x_1 + \beta z + \gamma x_2 z + \varepsilon, \\ &= \mu + \alpha x_1 + (\beta + \gamma x_2) z + \varepsilon. \end{aligned}$$

By choosing an appropriate value of x_2 to reduce the coefficient $\beta + \gamma x_2$, the impact of z on y can be reduced. Since β and γ are unknown, this can be achieved by using the control-by-noise interaction plots or other methods to be presented later.

Exploitation of Nonlinearity

- Nonlinearity between y and \mathbf{x} can be exploited for robustness if \mathbf{x}_0 , nominal values of \mathbf{x} , are control-factor settings and deviations of \mathbf{x} around \mathbf{x}_0 (i.e., $\mathbf{x} - \mathbf{x}_0$) are viewed as noise factors (called *internal noise*). Expand $y = f(\mathbf{x})$ around \mathbf{x}_0 ,

$$y \approx f(\mathbf{x}_0) + \sum_i \left(\frac{\partial f}{\partial x_i} \bigg|_{x_{i0}} \right) (x_i - x_{i0}).$$

- This leads to

$$\sigma^2 \approx \sum_i \left(\frac{\partial f}{\partial x_i} \bigg|_{x_{i0}} \right)^2 \sigma_i^2, \quad (1)$$

where $\sigma^2 = \text{var}(y)$, $\sigma_i^2 = \text{var}(x_i)$, each component x_i has mean x_{i0} and variance σ_i^2 .

- From (1), it can be seen that σ^2 can be reduced by choosing x_{i0} with a smaller slope $\frac{\partial f}{\partial x_i} \big|_{x_{i0}}$. This is demonstrated in Figure 1. Moving the nominal value a to b can reduce $\text{var}(y)$ because the slope at b is more flat. This is a **parameter design** step.
- On the other hand, reducing the variation of x around a can also reduce $\text{var}(y)$. This is a **tolerance design** step.



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Exploitation of Nonlinearity to Reduce Variation

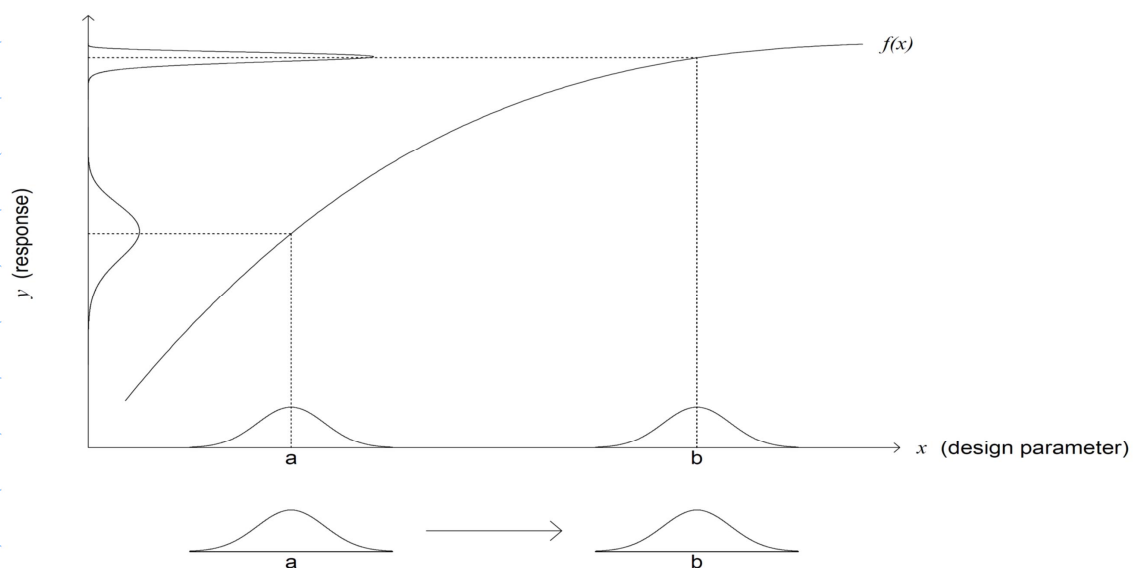


Figure 1: Exploiting the Nonlinearity of $f(x)$ to Reduce Variation

Cross Array and Location-Dispersion Modeling

- Cross array = control array \times noise array,
 - control array (or inner array)
= array (design matrix) for control factors,
 - noise array (or outer array)
= array (design matrix) for noise factors.
- Location-dispersion modeling
 - compute \bar{y}_i, s_i^2 based on the noise settings for the i^{th} control setting,
 - analyze \bar{y}_i (location), and $\ln s_i^2$ (dispersion), identify significant location and dispersion effects.

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Two-step Procedures for RPD Optimization

- **Two-Step Procedure for Nominal-the-Best Problem**
 - (i) select the levels of the dispersion factors to minimize dispersion,
 - (ii) select the level of the adjustment factor (if exists) to bring the location on target. (2)
- **Two-Step Procedure for Larger-the-Better and Smaller-the-Better Problems**
 - (i) select the levels of the location factors to maximize (or minimize) the location, (3)
 - (ii) select the levels of the dispersion factors that are not location factors to minimize dispersion.
- Note that the two steps in (3) are in reverse order from those in (2).
Reason: It is usually harder to increase or decrease the response y in the latter problem, so this step should be the first to perform.

Analysis of Layer Growth Experiment

- From the \bar{y}_i and $\ln s_i^2$ columns of Table 5 (LNp.10-14), compute the factorial effect estimates for location and dispersion respectively. (These numbers are not given in the textbook.) From the half-normal plots of these effects (Figure 2, LNp.10-15), D is significant for location and H , A for dispersion.

$$\begin{aligned}\hat{y} &= 14.352 + 0.402x_D, \\ \ln \hat{s}^2 &= -1.822 + 0.619x_A - 0.982x_H.\end{aligned}$$

- Two-step procedure:

(i) Choose A at the “–” level (continuous rotation) and H at the “+” level (nozzle position = 6).

(ii) By solving

$$\hat{y} = 14.352 + 0.402x_D = 14.5,$$

choose $-1 < x_D = 0.368 < 1$.

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Layer Growth Experiment: Analysis Results

Table 5: Means, Log Variances and SN Ratios, Layer Growth Experiment

Control Factor								\bar{y}_i	$\ln s_i^2$	$\ln \bar{y}_i^2$	$\hat{\eta}_i$
A	B	C	D	E	F	G	H				
–	–	–	+	–	–	–	–	14.79	–1.018	5.389	6.41
–	–	–	+	+	+	+	+	14.86	–3.879	5.397	9.28
–	–	+	–	–	–	+	+	14.00	–4.205	5.278	9.48
–	–	+	–	+	+	–	–	13.91	–1.623	5.265	6.89
–	+	–	–	–	+	–	+	14.15	–5.306	5.299	10.60
–	+	–	–	+	–	+	–	13.80	–1.236	5.250	6.49
–	+	+	+	–	+	+	–	14.73	–0.760	5.380	6.14
–	+	+	+	+	–	–	+	14.89	–1.503	5.401	6.90
+	–	–	–	–	+	+	–	13.93	–0.383	5.268	5.65
+	–	–	–	+	–	–	+	14.09	–2.180	5.291	7.47
+	–	+	+	–	+	–	+	14.79	–1.238	5.388	6.63
+	–	+	+	+	–	+	–	14.33	–0.868	5.324	6.19
+	+	–	+	–	–	+	+	14.77	–1.483	5.386	6.87
+	+	–	+	+	+	–	–	14.88	–0.418	5.400	5.82
+	+	+	–	–	–	–	–	13.76	–0.418	5.243	5.66
+	+	+	–	+	+	+	+	13.97	–2.636	5.274	7.91



Layer Growth Experiment: Plots

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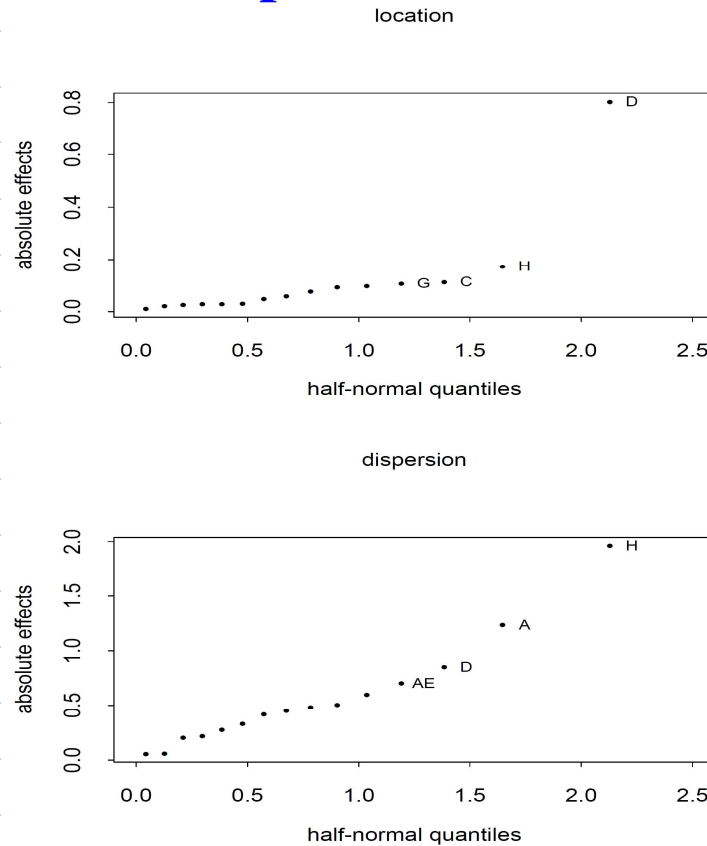


Figure 2: Half-Normal Plots of Location and Dispersion Effects, Layer Growth Experiment

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Analysis of Leaf Spring Experiment

- From the \bar{y}_i and $\ln s_i^2$ columns of Table 6 (LNp.10-17), compute the factorial effect estimates for location and dispersion respectively. Based on the half-normal plots in Figure 3 (LNp.10-18), B , C and E are significant for location, C is significant for dispersion:

$$\begin{aligned}\hat{y} &= 7.6360 + 0.1106x_B + 0.0881x_C + 0.0519x_E, \\ \ln \hat{s}^2 &= -3.6886 + 1.0901x_C.\end{aligned}$$

- Two-step procedure:

(i) Choose C at $-$.

(ii) With $x_C = -1$, $\hat{y} = 7.5479 + 0.1106x_B + 0.0519x_E$.

- * To achieve $\hat{y} = 8.0$, x_B and x_E must be chosen beyond $+1$ (e.g., $x_B = x_E = 2.78$). This is too drastic, and not validated by current data.
- * An alternative is to select $x_B = x_E = x_C = +1$ (not to follow the two-step procedure), then $\hat{y} = 7.89$ is closer to 8. (Note that $\hat{y} = 7.71$ with $B_+C_-E_+$.)
- * Reason for the breakdown of the 2-step procedure: its second step cannot achieve the target 8.0.





Leaf Spring Experiment: Analysis Results

Table 6: Means and Log Variances, Leaf Spring Experiment

Control Factor				\bar{y}_i	$\ln s_i^2$
<i>B</i>	<i>C</i>	<i>D</i>	<i>E</i>		
–	+	+	–	7.540	–2.4075
+	+	+	+	7.902	–2.6488
–	–	+	+	7.520	–6.9486
+	–	+	–	7.640	–4.8384
–	+	–	+	7.670	–2.3987
+	+	–	–	7.785	–2.9392
–	–	–	–	7.372	–3.2697
+	–	–	+	7.660	–4.0582



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Leaf Spring Experiment: Plots

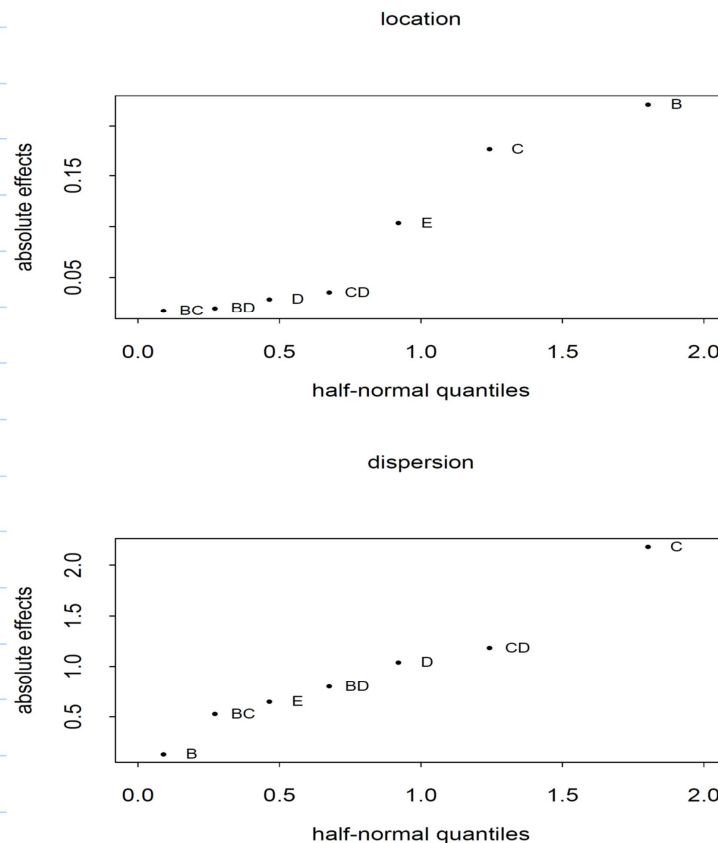


Figure 3: Half-Normal Plots of Location and Dispersion Effects, Leaf Spring Experiment

Response Modeling and Control-by-Noise Interaction Plots

- Response Model: model y_{ij} directly in terms of control and noise main effects and control-by-noise interactions.
 - half normal plot of various effects.
 - regression model fitting, obtaining \hat{y} .
- Make control-by-noise interaction plots for significant effects in \hat{y} , choose **robust** control settings at which y has a flatter relationship with noise factors.
- Compute $Var_N(\hat{y}_x)$ with respect to variation in the noise factors. Call $Var_N(\hat{y}_x)$ the **transmitted variance model**. Use it to identify control factor settings with small transmitted variance.

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Half-normal Plot, Layer Growth Experiment

- Define

$$M_l = (M_1 + M_2) - (M_3 + M_4),$$

$$M_q = (M_1 + M_4) - (M_2 + M_3),$$

$$M_c = (M_1 + M_3) - (M_2 + M_4),$$
- From Figure 4 (LNp.10-21), select the effects D, L, HL as the most significant effects.
- How to deal with the next cluster of effects in Figure 4? Use **step-down multiple comparisons**.
- After removing the top three points in Figure 4, make a half-normal plot (Figure 5, LNp.10-22) on the remaining points. The cluster of next four effects (M_l, H, CM_l, AHM_q) appear to be significant.



Half-normal Plot of Factorial Effects

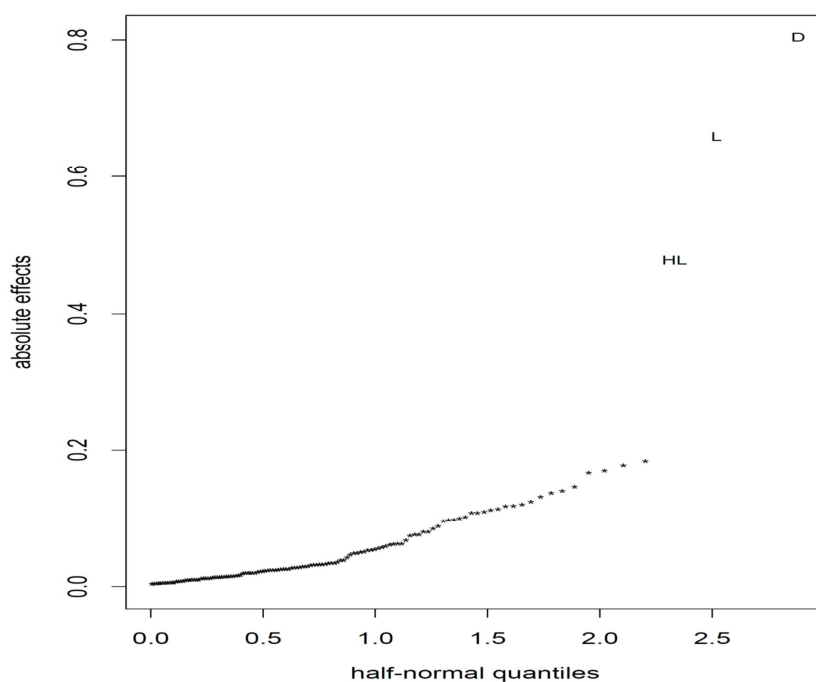


Figure 4: Half-Normal Plot of Response Model Effects,
Layer Growth Experiment

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Second Half-normal Plot of Factorial Effects

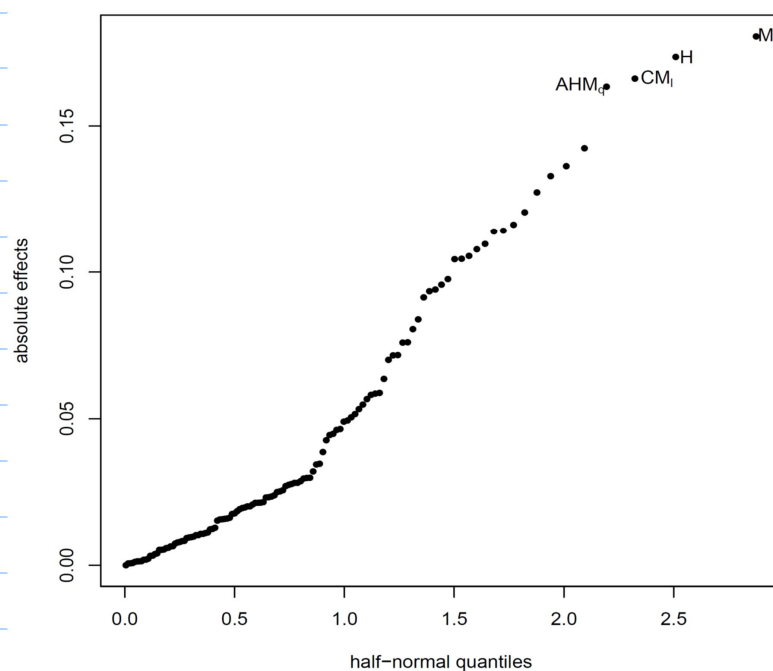


Figure 5: Second Half-Normal Plot of Response Model Effects,
Layer Growth Experiment

Control-by-noise Interaction Plots

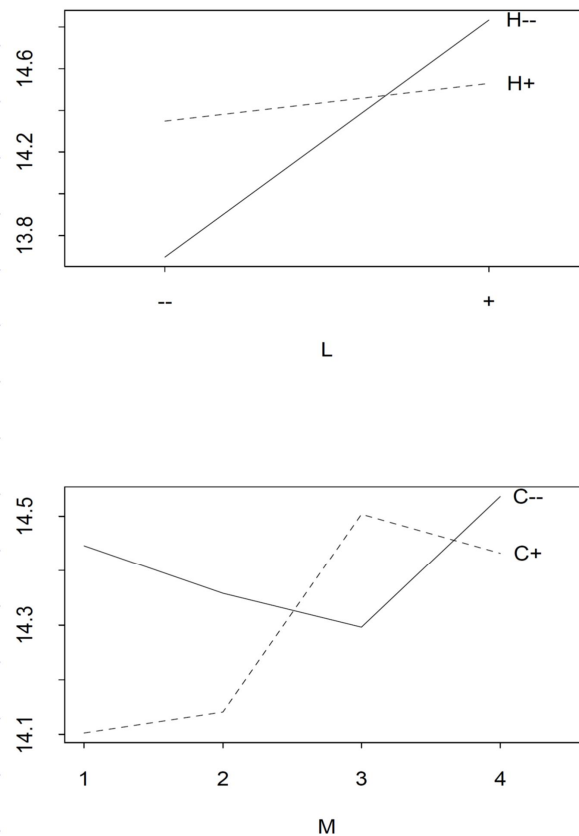


Figure 6: $H \times L$ and $C \times M$ Interaction Plots, Layer Growth Experiment

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Three-factor Interaction Plot: $A \times H \times M$

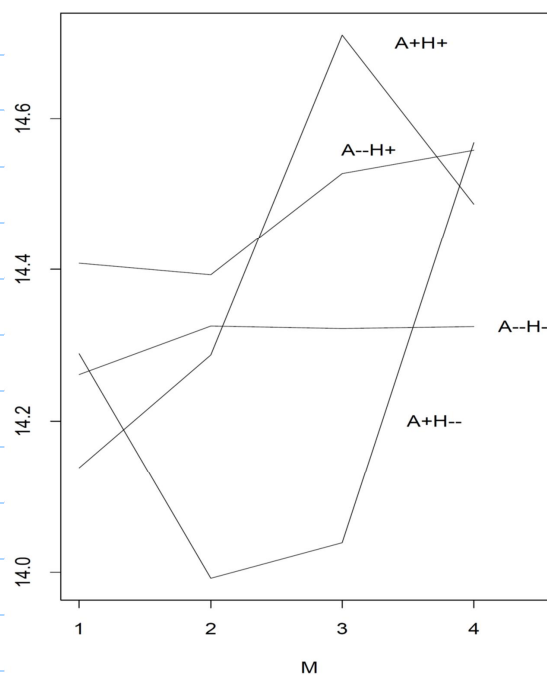


Figure 7: $A \times H \times M$ Interaction Plot, Layer Growth Experiment

Response Modeling, Layer Growth Experiment

- The following model is obtained:

$$\begin{aligned}\hat{y} = & 14.352 + 0.402x_D + 0.087x_H + 0.330x_L - 0.090x_{M_l} \\ & - 0.239x_Hx_L - 0.083x_Cx_{M_l} - 0.082x_Ax_Hx_{M_q}.\end{aligned}\quad (4)$$

- Recommendations:

H : – (position 2) to + (position 6)

A : + (oscillating) to – (continuous)

C : + (1210) to – (1220)

resulting in 37% reduction of thickness standard variation.

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Transmitted Variance Model

- Assume L , M_l and M_q are random variables, taking -1 and $+1$ with equal probabilities. This leads to

$$\begin{aligned}x_L^2 = x_{M_l}^2 = x_{M_q}^2 = x_A^2 = x_C^2 = x_H^2 &= 1, \\ E(x_L) = E(x_{M_l}) = E(x_{M_q}) &= 0, \\ \text{Cov}(x_L, x_{M_l}) = \text{Cov}(x_L, x_{M_q}) = \text{Cov}(x_{M_l}, x_{M_q}) &= 0, \\ \text{Var}(x_L) = \text{Var}(x_{M_l}) = \text{Var}(x_{M_q}) &= 1.\end{aligned}\quad (5)$$

- From (4) and (5), we have

$$\begin{aligned}\text{Var}_N(\hat{y}_x) &= (.330 - .239x_H)^2 \text{Var}(x_L) + (-.090 - .083x_C)^2 \text{Var}(x_{M_l}) \\ &\quad + (.082x_Ax_H)^2 \text{Var}(x_{M_q}) \\ &= \text{constant} + (.330 - .239x_H)^2 + (-.090 - .083x_C)^2 \\ &= \text{constant} - 2(.330)(.239)x_H + 2(.090)(.083)x_C \\ &= \text{constant} - .158x_H + .015x_C.\end{aligned}$$

- Choose $H+$ and $C-$. But factor A is not present here.
(Why? See explanation on textbook, p.532).

Estimation Capacity for Cross Arrays

- Example.
 - Control array is a 4-run 2_{III}^{3-1} design with

$$\mathbf{I} = ABC.$$

- Noise array is a 4-run 2_{III}^{3-1} design with

$$\mathbf{I} = abc.$$

- The resulting cross array is a 16-run 2_{III}^{6-2} design with

$$\mathbf{I} = ABC = abc = ABCabc.$$

- Easy to show that all 9 control-by-noise interactions are clear, (but not the 6 main effects).
- This is indeed a general result stated in next slide.

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Estimation Capacity for Cross Arrays (Cont.)

- **Theorem.** Suppose
 - a 2^{k-p} design d_C is chosen for the control array,
 - a 2^{m-q} design d_N is chosen for the noise array, and
 - a cross array, denoted by $d_C \otimes d_N$, is constructed from d_C and d_N .
- (i) If
 - * $\{\alpha_1, \dots, \alpha_A\}$ are the estimable factorial effects (among the control factors) in d_C and
 - * $\{\beta_1, \dots, \beta_B\}$ are the estimable factorial effects (among the noise factors) in d_N ,
 then $\{\alpha_i, \beta_j, \alpha_i \beta_j\}$ for $i = 1, \dots, A, j = 1, \dots, B$ are estimable in $d_C \otimes d_N$.
- (ii) All the km control-by-noise two-factor interactions (i.e., two-factor interactions between a control factor main effect and a noise factor main effect) are clear in $d_C \otimes d_N$.

Cross Arrays or Single Arrays?

- Three control factors A, B, C and two noise factors a, b :
Cross array requires $2^3 \otimes 2^2$ full factorial design (32 runs)
for allowing all main effects and two-factor interactions
to be clearly estimated.

- Use a single array with 16 runs for all five factors:
In the resolution V 2^{5-1} design with

$$\mathbf{I} = ABCab \quad \text{or} \quad \mathbf{I} = -ABCab,$$

all main effects and two-factor interactions are clear.

(See Table 7, LNp.10-30)

- Single arrays can have smaller runs, but
cross arrays are easier to use and interpret.



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32-run Cross Array and 16-run Single Arrays

Table 7: 32-Run Cross Array

	a				b			
	+ + - -				+ - + -			
Runs	A	B	C					
1-4	+	+	+	●	○	○	●	
5-8	+	+	-	○	●	●	○	
9-12	+	-	+	○	●	●	○	
13-16	+	-	-	●	○	○	●	
17-20	-	+	+	○	●	●	○	
21-24	-	+	-	●	○	○	●	
25-28	-	-	+	●	○	○	●	
29-32	-	-	-	○	●	●	○	

$$\bullet : \mathbf{I} = ABCab; \circ : \mathbf{I} = -ABCab$$

Comparison of Cross Arrays and Single Arrays

- Example 1 (continued)
 - An alternative is to choose a single array 2_{IV}^{6-2} design with $\mathbf{I} = \mathbf{ABCa} = \mathbf{ABbc} = \mathbf{abcC}$. This is not advisable because no 2fi's are clear and only main effects are clear. (Why? We need to have some clear control-by-noise interactions for robust optimization.)
 - A better one is to use a 2_{III}^{6-2} design with $\mathbf{I} = \mathbf{ABCa} = \mathbf{abc} = \mathbf{ABCbc}$. It has 9 clear effects: $A, B, C, Ab, Ac, Bb, Bc, Cb, Cc$ (3 control main effects and 6 control-by-noise interactions).

❖ Reading: textbook, 11.8

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Signal-to-Noise Ratio

- Taguchi's SN ratio $\hat{\eta}_{\mathbf{x}} = \ln \frac{\bar{y}_{\mathbf{x}}^2}{s_{\mathbf{x}}^2}$
- Two-step procedure:
 1. Select control factor levels to maximize SN ratio
 2. Use an adjustment factor to move mean on target.
- Limitations
 - maximizing $\bar{y}_{\mathbf{x}}^2$ not always desired.
 - little justification outside linear circuitry.
 - statistically justifiable only when $\text{Var}_N(y_{\mathbf{x}})$ is proportional to $[E_N(y_{\mathbf{x}})]^2$
- Recommendation: Use SN ratio sparingly. Better to use the location-dispersion modeling or the response modeling. The latter strategies can do whatever SN ratio analysis can achieve.





S/N Ratio Analysis for Layer Growth Experiment

- Based on the $\hat{\eta}_i$ column in Table 5 (LNp.10-14), compute the factorial effects using SN ratio. A half-normal plot of the effects for $\hat{\eta}_i$ is given in Figure 8 (LNp.10-34). From Figure 8, the conclusion is similar to location-dispersion analysis. Why? Using

$$\hat{\eta}_i = \ln \bar{y}_i^2 - \ln s_i^2,$$

and from Table 5, the variation among $\ln s_i^2$ is much larger than the variation among $\ln \bar{y}_i^2$; thus maximizing SN ratio is equivalent to minimizing $\ln s_i^2$ in this case.

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Half-normal Plot for S/N Ratio Analysis

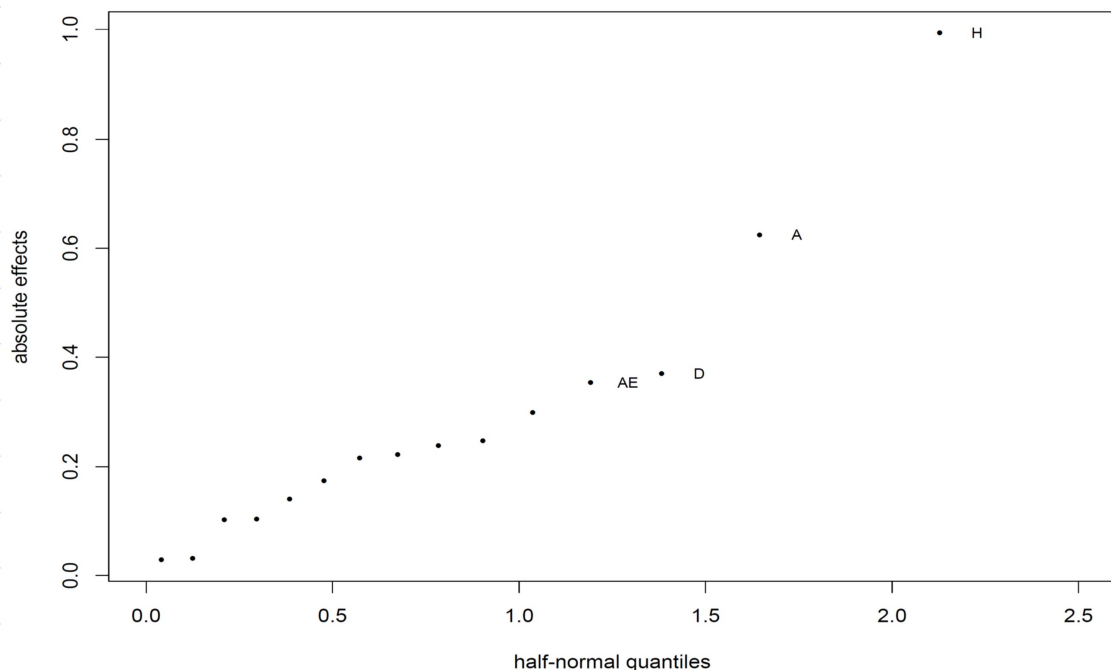


Figure 8: Half-Normal Plots of Effects Based on SN Ratio, Layer Growth Experiment